Issue Classification	fication	Application/Control No.	ò	Applicant(s)/Patent under Reexamination VIRAG ET AL.	ent under	
		Examiner Huynh, Son P		Art Unit 2623		
	ORIGINAL		INTE	RNATIONAL C	INTERNATIONAL CLASSIFICATION	
CLASS		SUBCLASS	CLAIMED	ED	NON-CLAIMED	
725	80	08	1 1 0 0 4 4 A Z Z Z Z Z	7 / 18		
CRO	CROSS REFERENCE(S)	NCE(S)	0 0 0	15 / 177		
CLASS SUB	SUBCLASS (ONE SUBCLASS	JBCLASS PER BLOCK)				
709 220	222	224				
713						
Son P. Huynh	06/19/2006				Total Claims Allowed:	
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